Correction to: Microstructure evolution and grain orientation in ITO targets and their effects on the film characteristics

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The authors regret that the printed version of the above article contained a number of errors. The correct and final version follows.

The reference number [29] should be marked in the captions of Figs. 1 and 2.

Another declaration should be noted here that Fig. 10a and c in this work should be referred by Fig. 8a and b in the reference [29] in the original article [J. Eur. Ceram. Soc. 38, 521–533 (2018)].

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